

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Mieher, et al.

Attorney Docket No.: KLA1P117/P1151

Application No.: 10/729,838

Examiner: Gordon J. Stock Jr.

Filed: December 5, 2003

Group: 2877

Title: APPARATUS AND METHODS FOR
DETECTING OVERLAY ERRORS USING SCATTEROMETRY Confirmation No.: 8320

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Signed: /Mia Mitchell-Haynes/

Typed: Mia Mitchell-Haynes

AMENDMENT A

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

It is respectfully submitted that the Examiner enters the following amendments in response to the Office Action dated 26 September 2006, a response to which is due 26 December 2006. A two-month extension is herein requested.

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begin on page 5 of this paper.

Remarks/Arguments begin on page 16 of this paper.